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Understanding Embedded - Microprocessors

Embedded microprocessors are specialized computing chips designed to perform specific tasks within an embedded system. Unlike general-purpose microprocessors found in personal computers, embedded microprocessors are tailored for dedicated functions within larger systems, offering optimized performance, efficiency, and reliability. These microprocessors are integral to the operation of countless electronic devices, providing the computational power necessary for controlling processes, handling data, and managing communications.

Applications of Embedded - Microprocessors

Embedded microprocessors are utilized across a broad spectrum of applications, making them indispensable in

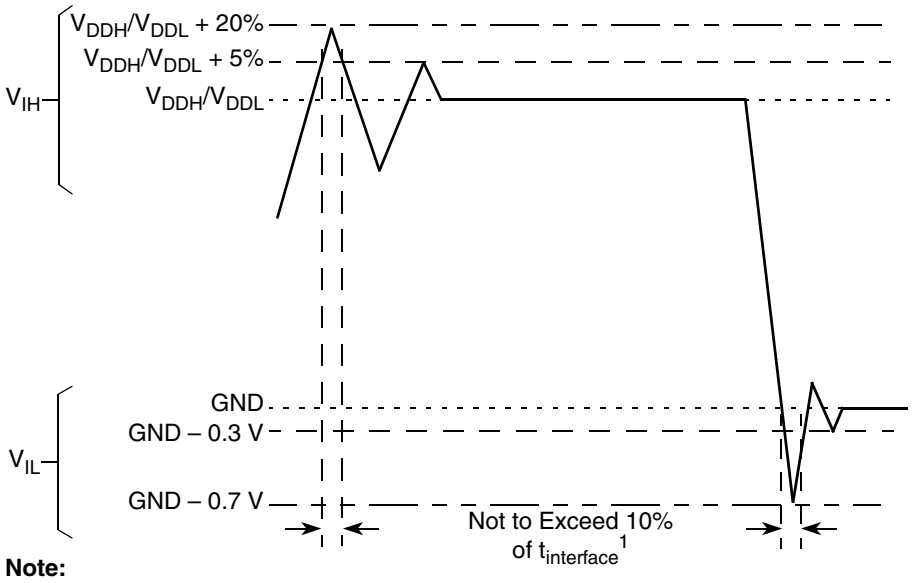
Details	
Product Status	Obsolete
Core Processor	MPC8xx
Number of Cores/Bus Width	1 Core, 32-Bit
Speed	50MHz
Co-Processors/DSP	Communications; CPM
RAM Controllers	DRAM
Graphics Acceleration	No
Display & Interface Controllers	-
Ethernet	10Mbps (2), 10/100Mbps (1)
SATA	-
USB	-
Voltage - I/O	3.3V
Operating Temperature	-40°C ~ 95°C (TA)
Security Features	-
Package / Case	357-BBGA
Supplier Device Package	357-PBGA (25x25)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/mpc860dtcvr50d4

2 Features

The following list summarizes the key MPC860 features:

- Embedded single-issue, 32-bit core (implementing the Power Architecture technology) with thirty-two 32-bit general-purpose registers (GPRs)
  - The core performs branch prediction with conditional prefetch without conditional execution.
  - 4- or 8-Kbyte data cache and 4- or 16-Kbyte instruction cache (see Table 1)
    - 16-Kbyte instruction caches are four-way, set-associative with 256 sets; 4-Kbyte instruction caches are two-way, set-associative with 128 sets.
    - 8-Kbyte data caches are two-way, set-associative with 256 sets; 4-Kbyte data caches are two-way, set-associative with 128 sets.
    - Cache coherency for both instruction and data caches is maintained on 128-bit (4-word) cache blocks.
    - Caches are physically addressed, implement a least recently used (LRU) replacement algorithm, and are lockable on a cache block basis.
  - MMUs with 32-entry TLB, fully-associative instruction, and data TLBs
  - MMUs support multiple page sizes of 4-, 16-, and 512-Kbytes, and 8-Mbytes; 16 virtual address spaces and 16 protection groups
  - Advanced on-chip-emulation debug mode
- Up to 32-bit data bus (dynamic bus sizing for 8, 16, and 32 bits)
- 32 address lines
- Operates at up to 80 MHz
- Memory controller (eight banks)
  - Contains complete dynamic RAM (DRAM) controller
  - Each bank can be a chip select or $\overline{\text{RAS}}$ to support a DRAM bank.
  - Up to 15 wait states programmable per memory bank
  - Glueless interface to DRAM, SIMMS, SRAM, EPROM, Flash EPROM, and other memory devices
  - DRAM controller programmable to support most size and speed memory interfaces
  - Four $\overline{\text{CAS}}$ lines, four $\overline{\text{WE}}$ lines, and one $\overline{\text{OE}}$ line
  - Boot chip-select available at reset (options for 8-, 16-, or 32-bit memory)
  - Variable block sizes (32 Kbytes to 256 Mbytes)
  - Selectable write protection
  - On-chip bus arbitration logic
- General-purpose timers
  - Four 16-bit timers or two 32-bit timers
  - Gate mode can enable/disable counting
  - Interrupt can be masked on reference match and event capture.

Figure 1 shows the undershoot and overshoot voltages at the interface of the MPC860.



Note:
1. $t_{interface}$ refers to the clock period associated with the bus clock interface.

Figure 1. Undershoot/Overshoot Voltage for V_{DDH} and V_{DDL}

4 Thermal Characteristics

Table 3. Package Description

Package Designator	Package Code (Case No.)	Package Description
ZP	5050 (1103-01)	PBGA 357 25*25*0.9P1.27
ZQ/VR	5058 (1103D-02)	PBGA 357 25*25*1.2P1.27

Table 4 shows the thermal characteristics for the MPC860.

Table 4. MPC860 Thermal Resistance Data

Rating	Environment		Symbol	ZP MPC860P	ZQ / VR MPC860P	Unit
Mold Compound Thickness				0.85	1.15	mm
Junction-to-ambient [1]	Natural convection	Single-layer board (1s)	$R_{\theta JA}$ [2]	34	34	°C/W
		Four-layer board (2s2p)	$R_{\theta JMA}$ [3]	22	22	
	Airflow (200 ft/min)	Single-layer board (1s)	$R_{\theta JMA}$ [3]	27	27	
		Four-layer board (2s2p)	$R_{\theta JMA}$ [3]	18	18	
Junction-to-board [4]			$R_{\theta JB}$	14	13	
Junction-to-case [5]			$R_{\theta JC}$	6	8	
Junction-to-package top [6]	Natural convection		Ψ_{JT}	2	2	

1 Junction temperature is a function of on-chip power dissipation, package thermal resistance, mounting site (board) temperature, ambient temperature, airflow, power dissipation of other components on the board, and board thermal resistance.

2 Per SEMI G38-87 and JEDEC JESD51-2 with the single-layer board horizontal.

3 Per JEDEC JESD51-6 with the board horizontal.

4 Thermal resistance between the die and the printed-circuit board per JEDEC JESD51-8. Board temperature is measured on the top surface of the board near the package.

5 Indicates the average thermal resistance between the die and the case top surface as measured by the cold plate method (MIL SPEC-883 Method 1012.1) with the cold plate temperature used for the case temperature. For exposed pad packages where the pad would be expected to be soldered, junction-to-case thermal resistance is a simulated value from the junction to the exposed pad without contact resistance.

6 Thermal characterization parameter indicating the temperature difference between the package top and the junction temperature per JEDEC JESD51-2.

Table 6. DC Electrical Specifications (continued)

Characteristic	Symbol	Min	Max	Unit
Input leakage current, V_{in} = 3.6 V (except TMS, $\overline{\text{TRST}}$, DSCK, and DSDI pins)	I_{In}	—	10	µA
Input leakage current, V_{in} = 0 V (except TMS, $\overline{\text{TRST}}$, DSCK, and DSDI pins)	I_{In}	—	10	µA
Input capacitance[2]	C_{in}	—	20	pF
Output high voltage, I_{OH} = –2.0 mA, V_{DDH} = 3.0 V (except XTAL, XFC, and open-drain pins)	V_{OH}	2.4	—	V
Output low voltage I_{OL} = 2.0 mA, CLKOUT I_{OL} = 3.2 mA [3] I_{OL} = 5.3 mA [4] I_{OL} = 7.0 mA, TXD1/PA14, TXD2/PA12 I_{OL} = 8.9 mA, $\overline{\text{TS}}$, $\overline{\text{TA}}$, $\overline{\text{TEA}}$, $\overline{\text{BI}}$, $\overline{\text{BB}}$, $\overline{\text{HRESET}}$, $\overline{\text{SRESET}}$	V_{OL}	—	0.5	V

1 V_{IL}(max) for the I^2C interface is 0.8 V rather than the 1.5 V as specified in the I^2C standard.

2 Input capacitance is periodically sampled.

3 A(0:31), TSIZ0/$\overline{\text{REG}}$, TSIZ1, D(0:31), DP(0:3)/$\overline{\text{IRQ}}$(3:6), RD/$\overline{\text{WR}}$, $\overline{\text{BURST}}$, $\overline{\text{RSV}}$/$\overline{\text{IRQ2}}$, IP_B(0:1)/IWP(0:1)/VFLS(0:1), IP_B2/IOIS16_B/AT2, IP_B3/IWP2/VF2, IP_B4/LWP0/VF0, IP_B5/LWP1/VF1, IP_B6/DSDI/AT0, IP_B7/PTR/AT3, RXD1/PA15, RXD2/PA13, L1TXDB/PA11, L1RXDB/PA10, L1TXDA/PA9, L1RXDA/PA8, TIN1/L1RCLKA/BRGO1/CLK1/PA7, BRGCLK1/$\overline{\text{TOUT1}}$/CLK2/PA6, TIN2/L1TCLKA/BRGO2/CLK3/PA5, $\overline{\text{TOUT2}}$/CLK4/PA4, TIN3/BRGO3/CLK5/PA3, BRGCLK2/L1RCLKB/$\overline{\text{TOUT3}}$/CLK6/PA2, TIN4/BRGO4/CLK7/PA1, L1TCLKB/$\overline{\text{TOUT4}}$/CLK8/PA0, $\overline{\text{REJCT1}}$/$\overline{\text{SPISEL}}$/PB31, SPICLK/PB30,SPIMOSI/PB29, BRGO4/SPIMISO/PB28, BRGO1/I2CSDA/PB27, BRGO2/I2CSCL/PB26, SMTXD1/PB25, SMRXD1/PB24, $\overline{\text{SMSYN1}}$/$\overline{\text{SDACK1}}$/PB23, $\overline{\text{SMSYN2}}$/$\overline{\text{SDACK2}}$/PB22, SMTXD2/L1CLKOB/PB21, SMRXD2/L1CLKOA/PB20, L1ST1/$\overline{\text{RTS1}}$/PB19, L1ST2/$\overline{\text{RTS2}}$/PB18, L1ST3/$\overline{\text{L1RQB}}$/PB17, L1ST4/$\overline{\text{L1RQA}}$/PB16, BRGO3/PB15, $\overline{\text{RSTRT1}}$/PB14, L1ST1/$\overline{\text{RTS1}}$/$\overline{\text{DREQ0}}$/PC15, L1ST2/$\overline{\text{RTS2}}$/$\overline{\text{DREQ1}}$/PC14, L1ST3/$\overline{\text{L1RQB}}$/PC13, L1ST4/$\overline{\text{L1RQA}}$/PC12, $\overline{\text{CTS1}}$/PC11, $\overline{\text{TGATE1}}$/$\overline{\text{CD1}}$/PC10, $\overline{\text{CTS2}}$/PC9, $\overline{\text{TGATE2}}$/$\overline{\text{CD2}}$/PC8, $\overline{\text{SDACK2}}$/L1TSYNCB/PC7, L1RSYNCB/PC6, $\overline{\text{SDACK1}}$/L1TSYNCA/PC5, L1RSYNCA/PC4, PD15, PD14, PD13, PD12, PD11, PD10, PD9, PD8, PD5, PD6, PD7, PD4, PD3, MII_MDC, MII_TX_ER, MII_EN, MII_MDIO, and MII_TXD[0:3]

4 $\overline{\text{BDIP}}$/$\overline{\text{GPL_B}}$(5), $\overline{\text{BR}}$, $\overline{\text{BG}}$, FRZ/$\overline{\text{IRQ6}}$, $\overline{\text{CS}}$(0:5), $\overline{\text{CS}}$(6)/$\overline{\text{CE}}$(1)_B, $\overline{\text{CS}}$(7)/$\overline{\text{CE}}$(2)_B, $\overline{\text{WE0}}$/$\overline{\text{BS_B0}}$/$\overline{\text{IORD}}$, $\overline{\text{WE1}}$/$\overline{\text{BS_B1}}$/$\overline{\text{IOWR}}$, $\overline{\text{WE2}}$/$\overline{\text{BS_B2}}$/$\overline{\text{PCOE}}$, $\overline{\text{WE3}}$/$\overline{\text{BS_B3}}$/$\overline{\text{PCWE}}$, $\overline{\text{BS_A}}$(0:3), $\overline{\text{GPL_A0}}$/$\overline{\text{GPL_B0}}$, $\overline{\text{OE}}$/$\overline{\text{GPL_A1}}$/$\overline{\text{GPL_B1}}$, $\overline{\text{GPL_A}}$(2:3)/$\overline{\text{GPL_B}}$(2:3)/$\overline{\text{CS}}$(2:3), UPWAITA/$\overline{\text{GPL_A4}}$, UPWAITB/$\overline{\text{GPL_B4}}$, $\overline{\text{GPL_A5}}$, ALE_A, $\overline{\text{CE}}$1_A, $\overline{\text{CE}}$2_A, ALE_B/DSCK/AT1, OP(0:1), OP2/MODCK1/$\overline{\text{STS}}$, OP3/MODCK2/DSDO, and BADDR(28:30)

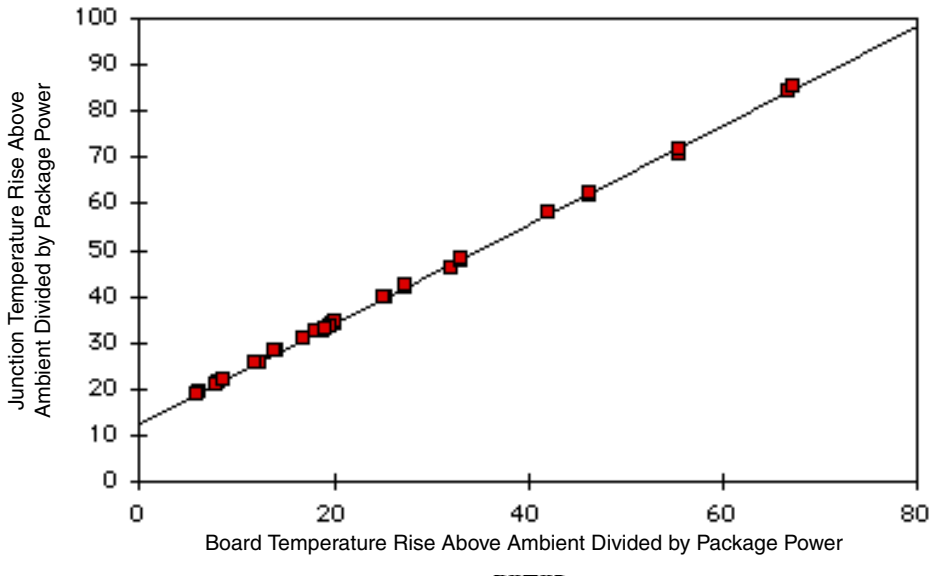


Figure 2. Effect of Board Temperature Rise on Thermal Behavior

If the board temperature is known, an estimate of the junction temperature in the environment can be made using the following equation:

$$T_J = T_B + (R_{\theta JB} \times P_D)$$

where:

$R_{\theta JB}$ = junction-to-board thermal resistance (ºC/W)

T_B = board temperature (ºC)

P_D = power dissipation in package

If the board temperature is known and the heat loss from the package case to the air can be ignored, acceptable predictions of junction temperature can be made. For this method to work, the board and board mounting must be similar to the test board used to determine the junction-to-board thermal resistance, namely a 2s2p (board with a power and a ground plane) and by attaching the thermal balls to the ground plane.

7.4 Estimation Using Simulation

When the board temperature is not known, a thermal simulation of the application is needed. The simple two-resistor model can be used with the thermal simulation of the application [2], or a more accurate and complex model of the package can be used in the thermal simulation.

7.5 Experimental Determination

To determine the junction temperature of the device in the application after prototypes are available, the thermal characterization parameter (Ψ_{JT}) can be used to determine the junction temperature with a measurement of the temperature at the top center of the package case using the following equation:

$$T_J = T_T + (\Psi_{JT} \times P_D)$$

Table 7. Bus Operation Timings (continued)

Num	Characteristic	33 MHz		40 MHz		50 MHz		66 MHz		Unit
		Min	Max	Min	Max	Min	Max	Min	Max	
B29d	$\overline{WE}$(0:3) negated to D(0:31), DP(0:3) High-Z GPCM write access, TRLX = 1, CSNT = 1, EBDF = 0	43.45	—	35.5	—	28.00	—	20.73	—	ns
B29e	$\overline{CS}$ negated to D(0:31), DP(0:3) High-Z GPCM write access, TRLX = 1, CSNT = 1, ACS = 10, or ACS = 11, EBDF = 0	43.45	—	35.5	—	28.00	—	29.73	—	ns
B29f	$\overline{WE}$(0:3) negated to D(0:31), DP(0:3) High-Z GPCM write access, TRLX = 0, CSNT = 1, EBDF = 1	8.86	—	6.88	—	5.00	—	3.18	—	ns
B29g	$\overline{CS}$ negated to D(0:31), DP(0:3) High-Z GPCM write access, TRLX = 0, CSNT = 1, ACS = 10, or ACS = 11, EBDF = 1	8.86	—	6.88	—	5.00	—	3.18	—	ns
B29h	$\overline{WE}$(0:3) negated to D(0:31), DP(0:3) High-Z GPCM write access, TRLX = 1, CSNT = 1, EBDF = 1	38.67	—	31.38	—	24.50	—	17.83	—	ns
B29i	$\overline{CS}$ negated to D(0:31), DP(0:3) High-Z GPCM write access, TRLX = 1, CSNT = 1, ACS = 10, or ACS = 11, EBDF = 1	38.67	—	31.38	—	24.50	—	17.83	—	ns
B30	$\overline{CS}$, $\overline{WE}$(0:3) negated to A(0:31), BADDR(28:30) invalid GPCM write access [8]	5.58	—	4.25	—	3.00	—	1.79	—	ns
B30a	$\overline{WE}$(0:3) negated to A(0:31), BADDR(28:30) invalid GPCM, write access, TRLX = 0, CSNT = 1, $\overline{CS}$ negated to A(0:31) invalid GPCM write access, TRLX = 0, CSNT = 1 ACS = 10, or ACS = 11, EBDF = 0	13.15	—	10.50	—	8.00	—	5.58	—	ns
B30b	$\overline{WE}$(0:3) negated to A(0:31), invalid GPCM BADDR(28:30) invalid GPCM write access, TRLX = 1, CSNT = 1. $\overline{CS}$ negated to A(0:31), Invalid GPCM, write access, TRLX = 1, CSNT = 1, ACS = 10, or ACS = 11, EBDF = 0	43.45	—	35.50	—	28.00	—	20.73	—	ns
B30c	$\overline{WE}$(0:3) negated to A(0:31), BADDR(28:30) invalid GPCM write access, TRLX = 0, CSNT = 1. $\overline{CS}$ negated to A(0:31) invalid GPCM write access, TRLX = 0, CSNT = 1, ACS = 10, ACS = 11, EBDF = 1	8.36	—	6.38	—	4.50	—	2.68	—	ns
B30d	$\overline{WE}$(0:3) negated to A(0:31), BADDR(28:30) invalid GPCM write access, TRLX = 1, CSNT =1. $\overline{CS}$ negated to A(0:31) invalid GPCM write access TRLX = 1, CSNT = 1, ACS = 10, or ACS = 11, EBDF = 1	38.67	—	31.38	—	24.50	—	17.83	—	ns
B31	CLKOUT falling edge to $\overline{CS}$ valid—as requested by control bit CST4 in the corresponding word in UPM	1.50	6.00	1.50	6.00	1.50	6.00	1.50	6.00	ns

Table 7. Bus Operation Timings (continued)

Num	Characteristic	33 MHz		40 MHz		50 MHz		66 MHz		Unit
		Min	Max	Min	Max	Min	Max	Min	Max	
B35	A(0:31), BADDR(28:30) to $\overline{CS}$ valid—as requested by control bit BST4 in the corresponding word in UPM	5.58	—	4.25	—	3.00	—	1.79	—	ns
B35a	A(0:31), BADDR(28:30), and D(0:31) to $\overline{BS}$ valid—as requested by control bit BST1 in the corresponding word in UPM	13.15	—	10.50	—	8.00	—	5.58	—	ns
B35b	A(0:31), BADDR(28:30), and D(0:31) to $\overline{BS}$ valid—as requested by control bit BST2 in the corresponding word in UPM	20.73	—	16.75	—	13.00	—	9.36	—	ns
B36	A(0:31), BADDR(28:30), and D(0:31) to $\overline{GPL}$ valid—as requested by control bit GxT4 in the corresponding word in UPM	5.58	—	4.25	—	3.00	—	1.79	—	ns
B37	UPWAIT valid to CLKOUT falling edge[9]	6.00	—	6.00	—	6.00	—	6.00	—	ns
B38	CLKOUT falling edge to UPWAIT valid[9]	1.00	—	1.00	—	1.00	—	1.00	—	ns
B39	$\overline{AS}$ valid to CLKOUT rising edge[10]	7.00	—	7.00	—	7.00	—	7.00	—	ns
B40	A(0:31), TSIZ(0:1), RD/$\overline{WR}$, $\overline{BURST}$, valid to CLKOUT rising edge	7.00	—	7.00	—	7.00	—	7.00	—	ns
B41	$\overline{TS}$ valid to CLKOUT rising edge (setup time)	7.00	—	7.00	—	7.00	—	7.00	—	ns
B42	CLKOUT rising edge to $\overline{TS}$ valid (hold time)	2.00	—	2.00	—	2.00	—	2.00	—	ns
B43	$\overline{AS}$ negation to memory controller signals negation	—	TBD	—	TBD	—	TBD	—	TBD	ns

1 Phase and frequency jitter performance results are only valid if the input jitter is less than the prescribed value.

2 If the rate of change of the frequency of EXTAL is slow (that is, it does not jump between the minimum and maximum values in one cycle) or the frequency of the jitter is fast (that is, it does not stay at an extreme value for a long time) then the maximum allowed jitter on EXTAL can be up to 2%.

3 The timings specified in B4 and B5 are based on full strength clock.

4 The timing for $\overline{BR}$ output is relevant when the MPC860 is selected to work with external bus arbiter. The timing for $\overline{BG}$ output is relevant when the MPC860 is selected to work with internal bus arbiter.

5 The timing required for $\overline{BR}$ input is relevant when the MPC860 is selected to work with internal bus arbiter. The timing for $\overline{BG}$ input is relevant when the MPC860 is selected to work with external bus arbiter.

6 The D(0:31) and DP(0:3) input timings B18 and B19 refer to the rising edge of the CLKOUT in which the $\overline{TA}$ input signal is asserted.

7 The D(0:31) and DP(0:3) input timings B20 and B21 refer to the falling edge of the CLKOUT. This timing is valid only for read accesses controlled by chip-selects under control of the UPM in the memory controller, for data beats where DLT3 = 1 in the UPM RAM words. (This is only the case where data is latched on the falling edge of CLKOUT.)

8 The timing B30 refers to $\overline{CS}$ when ACS = 00 and to $\overline{WE}$(0:3) when CSNT = 0.

9 The signal UPWAIT is considered asynchronous to the CLKOUT and synchronized internally. The timings specified in B37 and B38 are specified to enable the freeze of the UPM output signals as described in Figure 18.

10 The $\overline{AS}$ signal is considered asynchronous to the CLKOUT. The timing B39 is specified in order to allow the behavior specified in Figure 21.

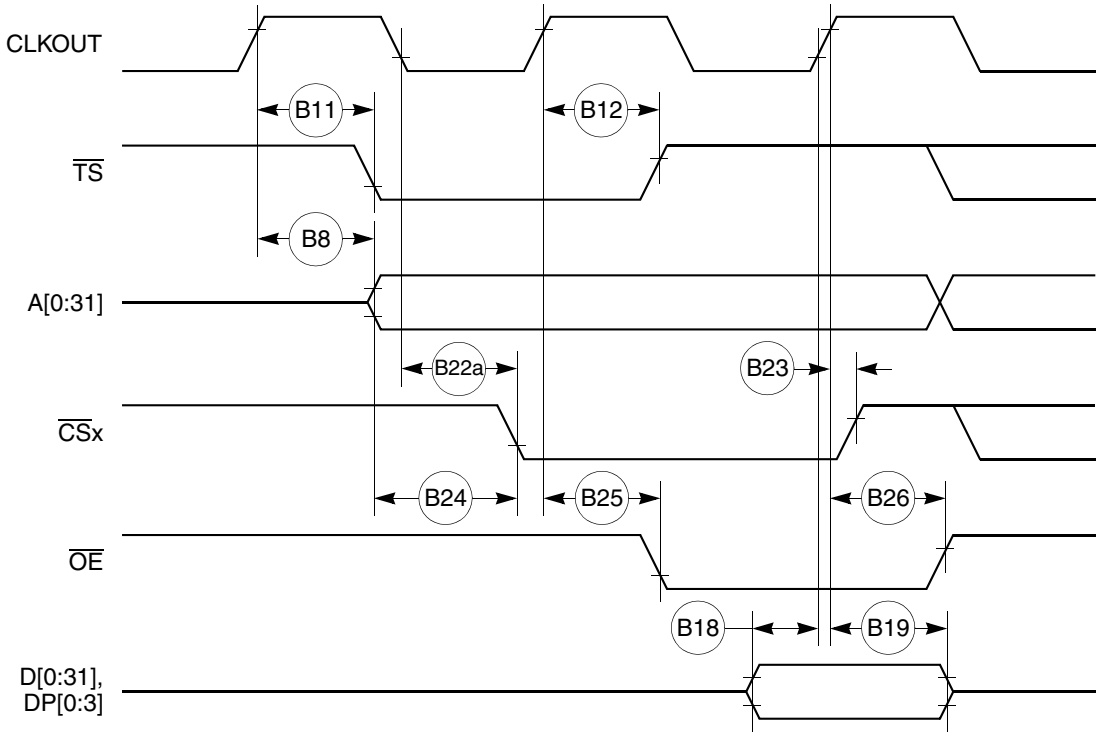


Figure 11. External Bus Read Timing (GPCM Controlled—TRLX = 0, ACS = 10)

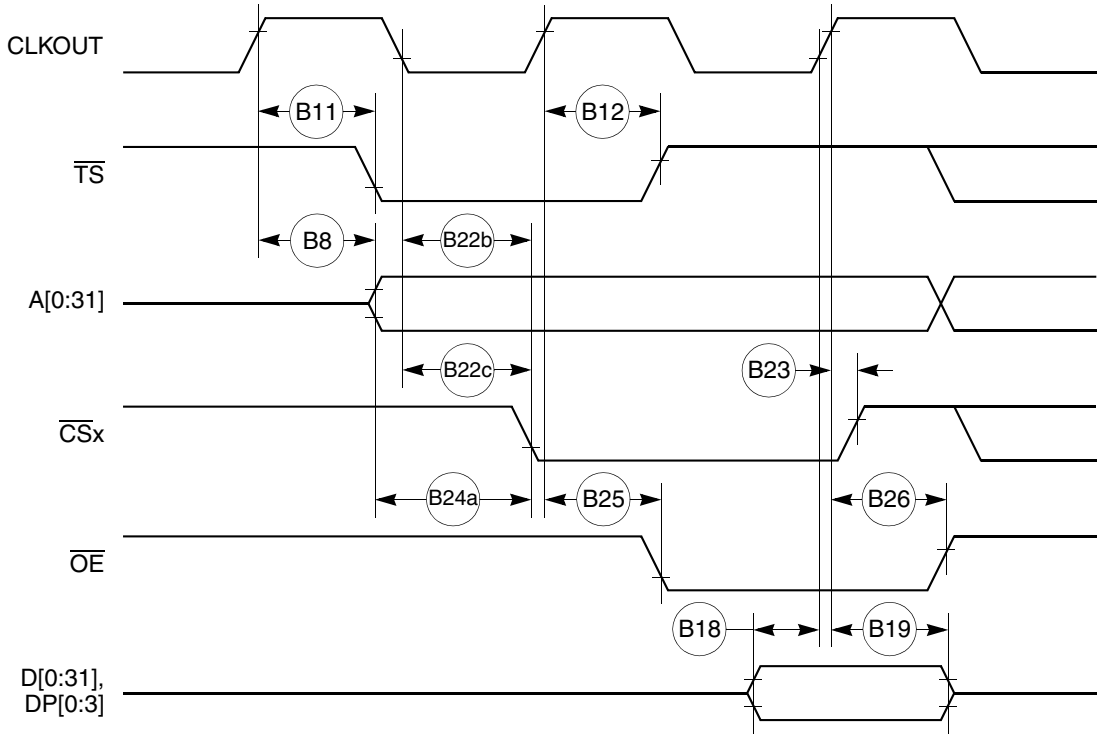


Figure 12. External Bus Read Timing (GPCM Controlled—TRLX = 0, ACS = 11)

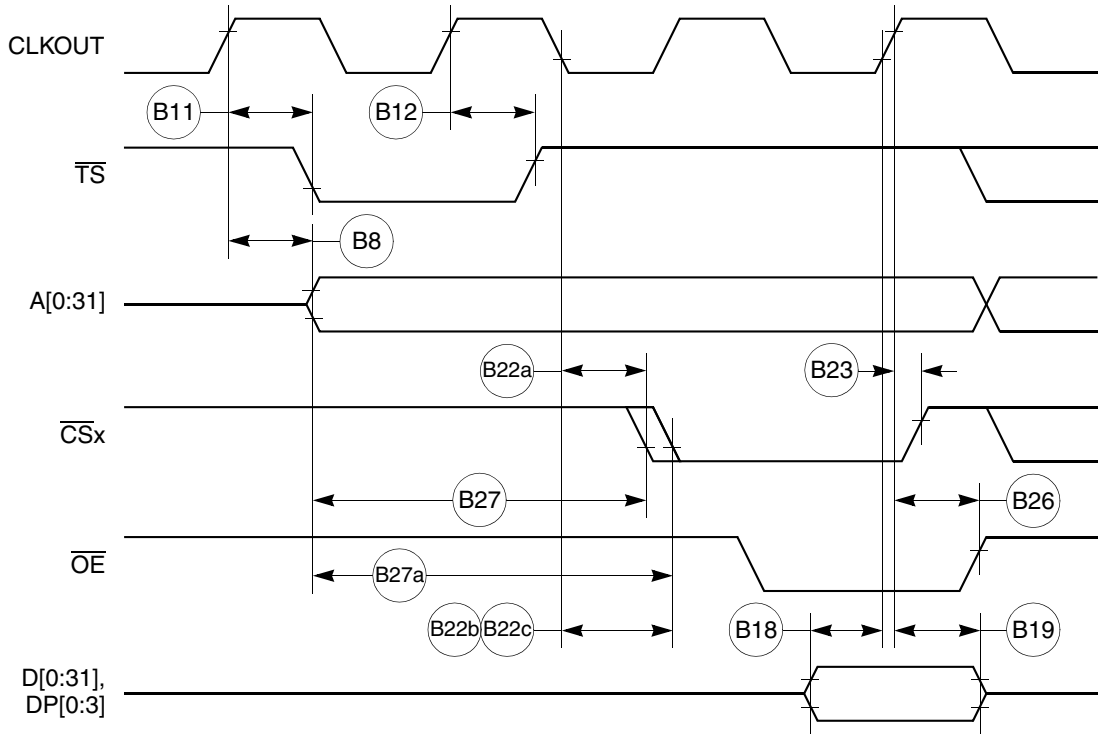


Figure 13. External Bus Read Timing (GPCM Controlled—TRLX = 0 or 1, ACS = 10, ACS = 11)

Figure 14 through Figure 16 provide the timing for the external bus write controlled by various GPCM factors.

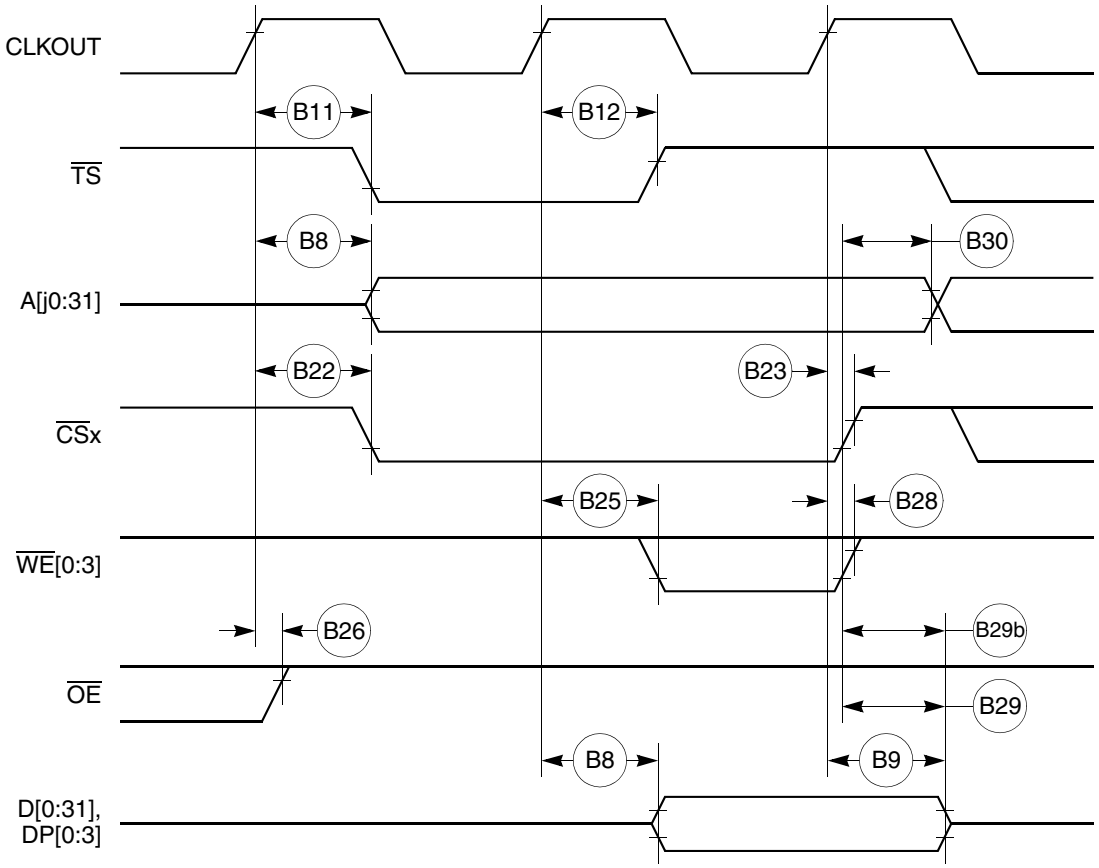


Figure 14. External Bus Write Timing (GPCM Controlled—TRLX = 0 or 1, CSNT = 0)

Table 10 shows the PCMCIA port timing for the MPC860.

Table 10. PCMCIA Port Timing

Num	Characteristic	33 MHz		40 MHz		50 MHz		66 MHz		Unit
		Min	Max	Min	Max	Min	Max	Min	Max	
P57	CLKOUT to OPx valid	—	19.00	—	19.00	—	19.00	—	19.00	ns
P58	$\overline{\text{HRESET}}$ negated to OPx drive[1]	25.73	—	21.75	—	18.00	—	14.36	—	ns
P59	IP_Xx valid to CLKOUT rising edge	5.00	—	5.00	—	5.00	—	5.00	—	ns
P60	CLKOUT rising edge to IP_Xx invalid	1.00	—	1.00	—	1.00	—	1.00	—	ns

1 OP2 and OP3 only.

Figure 28 provides the PCMCIA output port timing for the MPC860.

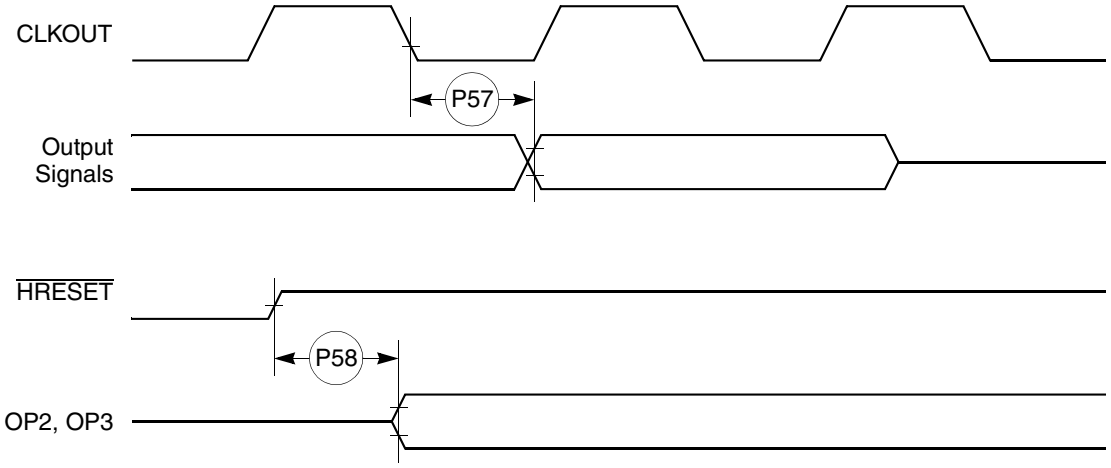


Figure 28. PCMCIA Output Port Timing

Figure 29 provides the PCMCIA output port timing for the MPC860.

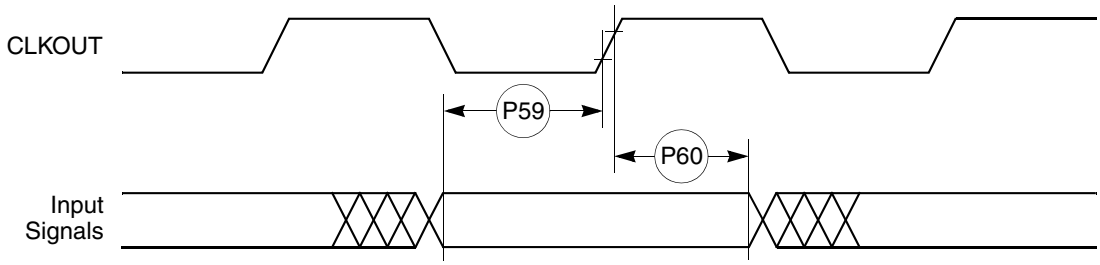


Figure 29. PCMCIA Input Port Timing

Table 11 shows the debug port timing for the MPC860.

Table 11. Debug Port Timing

Num	Characteristic	All Frequencies		Unit
		Min	Max	
P61	DSCK cycle time	$3 \times T_{CLOCKOUT}$	—	—
P62	DSCK clock pulse width	$1.25 \times T_{CLOCKOUT}$	—	—
P63	DSCK rise and fall times	0.00	3.00	ns
P64	DSDI input data setup time	8.00	—	ns
P65	DSDI data hold time	5.00	—	ns
P66	DSCK low to DSDO data valid	0.00	15.00	ns
P67	DSCK low to DSDO invalid	0.00	2.00	ns

Figure 30 provides the input timing for the debug port clock.

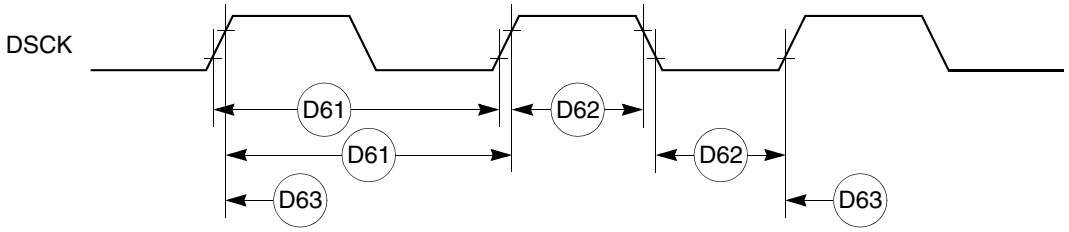


Figure 30. Debug Port Clock Input Timing

Figure 31 provides the timing for the debug port.

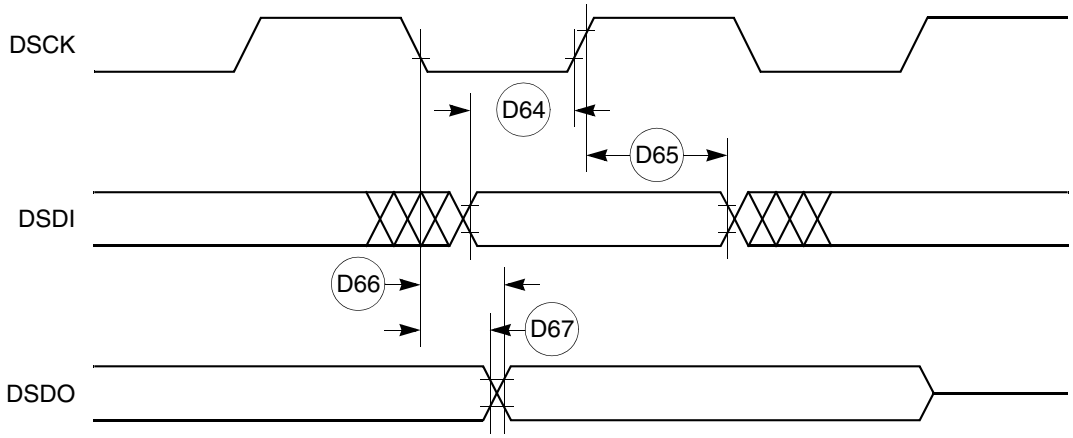


Figure 31. Debug Port Timings

Table 12 shows the reset timing for the MPC860.

Table 12. Reset Timing

Num	Characteristic	33 MHz		40 MHz		50 MHz		66 MHz		Unit
		Min	Max	Min	Max	Min	Max	Min	Max	
R69	CLKOUT to $\overline{\text{HRESET}}$ high impedance	—	20.00	—	20.00	—	20.00	—	20.00	ns
R70	CLKOUT to $\overline{\text{SRESET}}$ high impedance	—	20.00	—	20.00	—	20.00	—	20.00	ns
R71	$\overline{\text{RSTCONF}}$ pulse width	515.15	—	425.00		340.00	—	257.58	—	ns
R72	—	—	—	—	—	—	—	—	—	
R73	Configuration data to HRESET rising edge setup time	504.55	—	425.00	—	350.00	—	277.27	—	ns
R74	Configuration data to $\overline{\text{RSTCONF}}$ rising edge setup time	350.00	—	350.00	—	350.00	—	350.00	—	ns
R75	Configuration data hold time after $\overline{\text{RSTCONF}}$ negation	0.00	—	0.00	—	0.00	—	0.00	—	ns
R76	Configuration data hold time after $\overline{\text{HRESET}}$ negation	0.00	—	0.00	—	0.00	—	0.00	—	ns
R77	$\overline{\text{HRESET}}$ and $\overline{\text{RSTCONF}}$ asserted to data out drive	—	25.00		25.00	—	25.00	—	25.00	ns
R78	$\overline{\text{RSTCONF}}$ negated to data out high impedance	—	25.00	—	25.00	—	25.00	—	25.00	ns
R79	CLKOUT of last rising edge before chip three-state $\overline{\text{HRESET}}$ to data out high impedance	—	25.00	—	25.00	—	25.00	—	25.00	ns
R80	DSDI, DSCK setup	90.91	—	75.00	—	60.00	—	45.45	—	ns
R81	DSDI, DSCK hold time	0.00	—	0.00	—	0.00	—	0.00	—	ns
R82	$\overline{\text{SRESET}}$ negated to CLKOUT rising edge for DSDI and DSCK sample	242.42	—	200.00	—	160.00	—	121.21	—	ns

Figure 32 shows the reset timing for the data bus configuration.

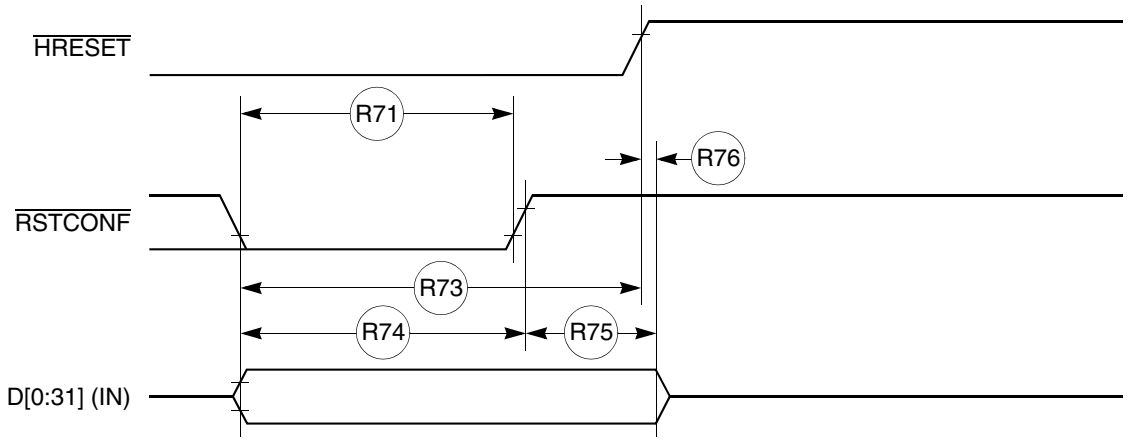


Figure 32. Reset Timing—Configuration from Data Bus

Figure 33 provides the reset timing for the data bus weak drive during configuration.

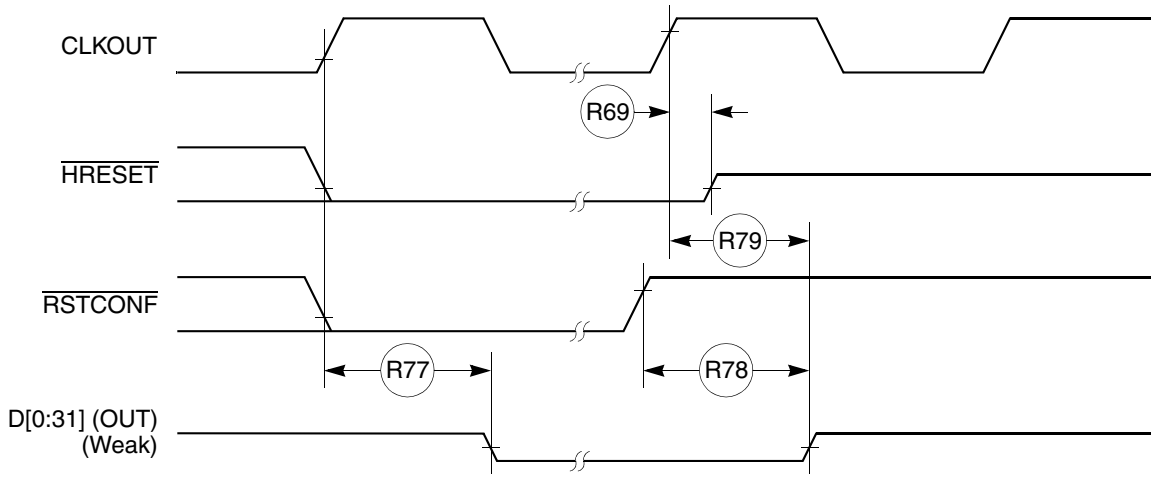


Figure 33. Reset Timing—Data Bus Weak Drive During Configuration

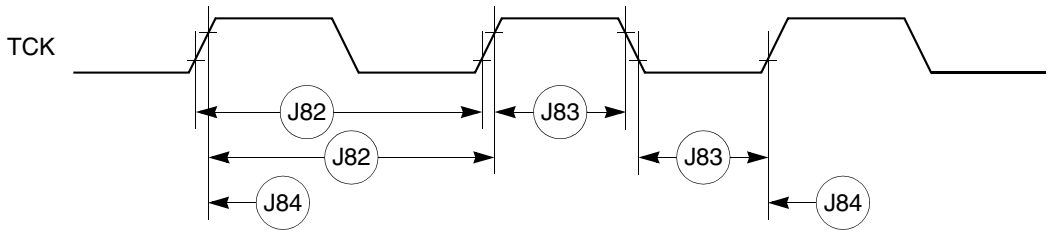


Figure 35. JTAG Test Clock Input Timing

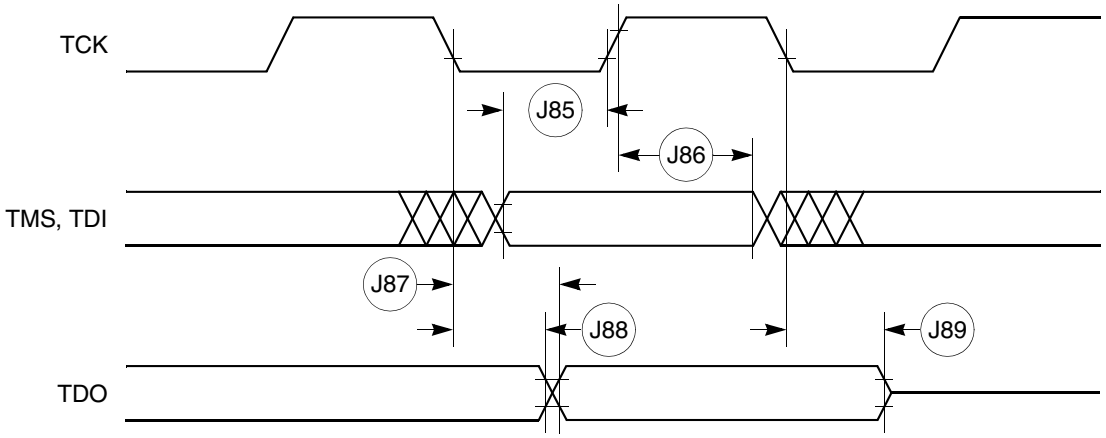


Figure 36. JTAG Test Access Port Timing Diagram

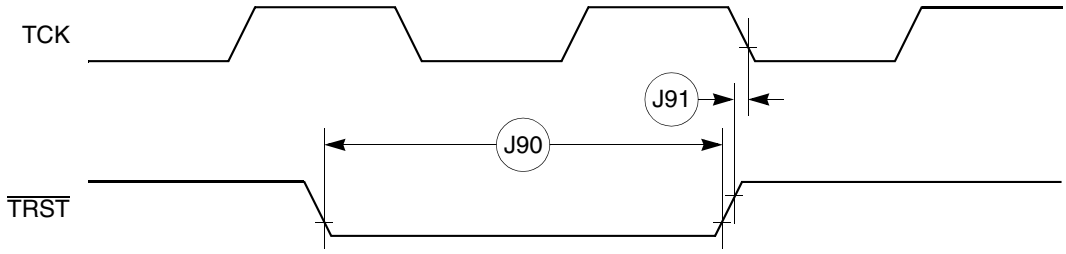


Figure 37. JTAG $\overline{\text{TRST}}$ Timing Diagram

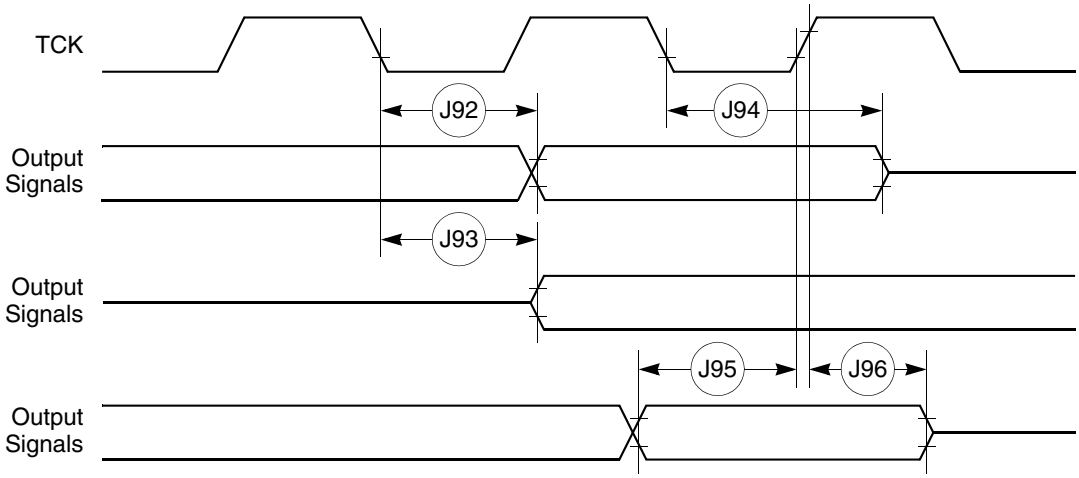


Figure 38. Boundary Scan (JTAG) Timing Diagram

11.4 Baud Rate Generator AC Electrical Specifications

Table 17 provides the baud rate generator timings as shown in Figure 49.

Table 17. Baud Rate Generator Timing

Num	Characteristic	All Frequencies		Unit
		Min	Max	
50	BRGO rise and fall time	—	10	ns
51	BRGO duty cycle	40	60	%
52	BRGO cycle	40	—	ns

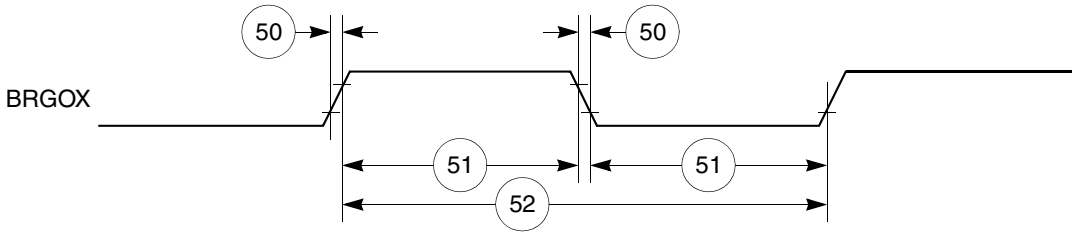


Figure 49. Baud Rate Generator Timing Diagram

11.5 Timer AC Electrical Specifications

Table 18 provides the general-purpose timer timings as shown in Figure 50.

Table 18. Timer Timing

Num	Characteristic	All Frequencies		Unit
		Min	Max	
61	TIN/$\overline{\text{TGATE}}$ rise and fall time	10	—	ns
62	TIN/$\overline{\text{TGATE}}$ low time	1	—	CLK
63	TIN/$\overline{\text{TGATE}}$ high time	2	—	CLK
64	TIN/$\overline{\text{TGATE}}$ cycle time	3	—	CLK
65	CLKO low to $\overline{\text{TOUT}}$ valid	3	25	ns

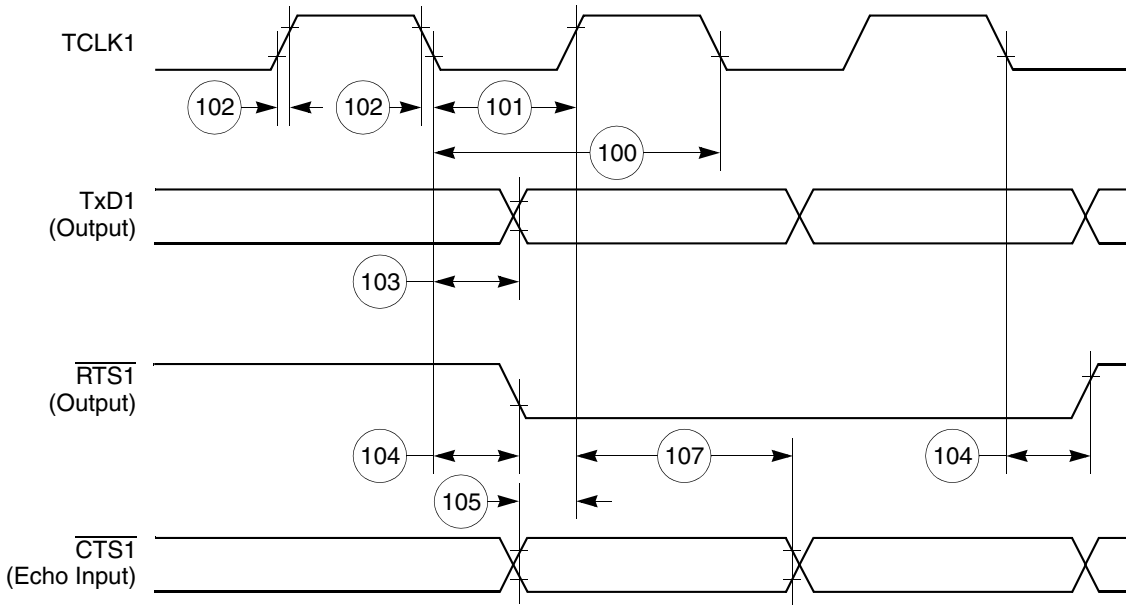


Figure 58. HDLC Bus Timing Diagram

11.8 Ethernet Electrical Specifications

Table 22 provides the Ethernet timings as shown in Figure 59 through Figure 63.

Table 22. Ethernet Timing

Num	Characteristic	All Frequencies		Unit
		Min	Max	
120	CLSN width high	40	—	ns
121	RCLK1 rise/fall time	—	15	ns
122	RCLK1 width low	40	—	ns
123	RCLK1 clock period[1]	80	120	ns
124	RXD1 setup time	20	—	ns
125	RXD1 hold time	5	—	ns
126	RENA active delay (from RCLK1 rising edge of the last data bit)	10	—	ns
127	RENA width low	100	—	ns
128	TCLK1 rise/fall time	—	15	ns
129	TCLK1 width low	40	—	ns
130	TCLK1 clock period[1]	99	101	ns
131	TXD1 active delay (from TCLK1 rising edge)	10	50	ns
132	TXD1 inactive delay (from TCLK1 rising edge)	10	50	ns
133	TENA active delay (from TCLK1 rising edge)	10	50	ns
134	TENA inactive delay (from TCLK1 rising edge)	10	50	ns

Table 22. Ethernet Timing (continued)

Num	Characteristic	All Frequencies		Unit
		Min	Max	
135	$\overline{\text{RSTRT}}$ active delay (from TCLK1 falling edge)	10	50	ns
136	$\overline{\text{RSTRT}}$ inactive delay (from TCLK1 falling edge)	10	50	ns
137	$\overline{\text{REJECT}}$ width low	1	—	CLK
138	CLKO1 low to $\overline{\text{SDACK}}$ asserted[2]	—	20	ns
139	CLKO1 low to $\overline{\text{SDACK}}$ negated[2]	—	20	ns

1 The ratios SYNCCLK/RCLK1 and SYNCCLK/TCLK1 must be greater than or equal to 2/1.
2 $\overline{\text{SDACK}}$ is asserted whenever the SDMA writes the incoming frame DA into memory.

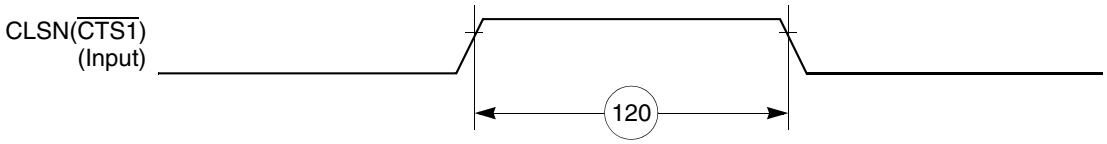


Figure 59. Ethernet Collision Timing Diagram

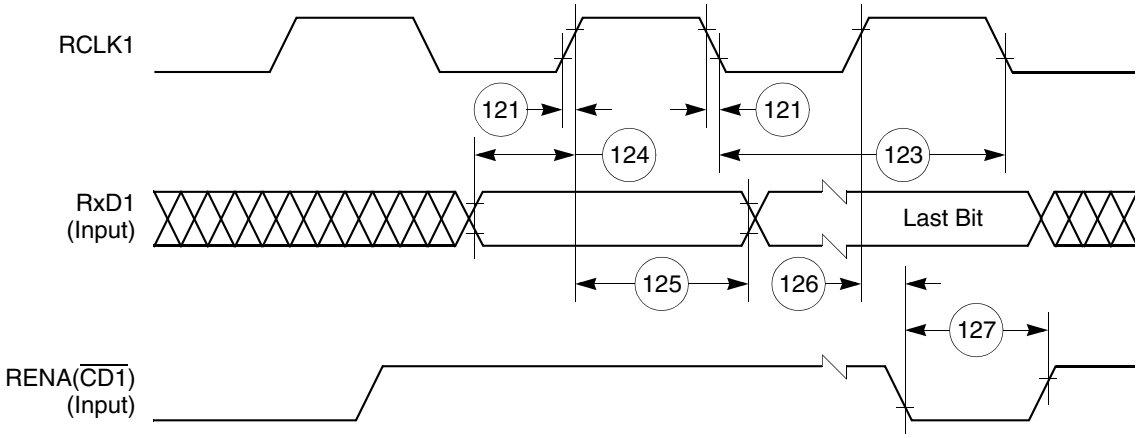


Figure 60. Ethernet Receive Timing Diagram

11.12 I²C AC Electrical Specifications

Table 26 provides the I²C (SCL < 100 kHz) timings.

Table 26. I²C Timing (SCL < 100 kHz)

Num	Characteristic	All Frequencies		Unit
		Min	Max	
200	SCL clock frequency (slave)	0	100	kHz
200	SCL clock frequency (master)[1]	1.5	100	kHz
202	Bus free time between transmissions	4.7	—	µs
203	Low period of SCL	4.7	—	µs
204	High period of SCL	4.0	—	µs
205	Start condition setup time	4.7	—	µs
206	Start condition hold time	4.0	—	µs
207	Data hold time	0	—	µs
208	Data setup time	250	—	ns
209	SDL/SCL rise time	—	1	µs
210	SDL/SCL fall time	—	300	ns
211	Stop condition setup time	4.7	—	µs

1 SCL frequency is given by SCL = BRGCLK_frequency / ((BRG register + 3 × pre_scaler × 2).
The ratio SYNCCLK/(BRGCLK/pre_scaler) must be greater than or equal to 4/1.

Table 27 provides the I²C (SCL > 100 kHz) timings.

Table 27. . I²C Timing (SCL > 100 kHz)

Num	Characteristic	Expression	All Frequencies		Unit
			Min	Max	
200	SCL clock frequency (slave)	fSCL	0	BRGCLK/48	Hz
200	SCL clock frequency (master)[1]	fSCL	BRGCLK/16512	BRGCLK/48	Hz
202	Bus free time between transmissions		1/(2.2 * fSCL)	—	s
203	Low period of SCL		1/(2.2 * fSCL)	—	s
204	High period of SCL		1/(2.2 * fSCL)	—	s
205	Start condition setup time		1/(2.2 * fSCL)	—	s
206	Start condition hold time		1/(2.2 * fSCL)	—	s
207	Data hold time		0	—	s
208	Data setup time		1/(40 * fSCL)	—	s
209	SDL/SCL rise time		—	1/(10 * fSCL)	s
210	SDL/SCL fall time		—	1/(33 * fSCL)	s
211	Stop condition setup time		1/2(2.2 * fSCL)	—	s

1 SCL frequency is given by SCL = BRGCLK_frequency / ((BRG register + 3) × pre_scaler × 2).
The ratio SYNCCLK/(BRGCLK / pre_scaler) must be greater than or equal to 4/1.

13 FEC Electrical Characteristics

This section provides the AC electrical specifications for the Fast Ethernet controller (FEC). Note that the timing specifications for the MII signals are independent of system clock frequency (part speed designation). Also, MII signals use TTL signal levels compatible with devices operating at either 5.0 V or 3.3 V.

13.1 MII Receive Signal Timing (MII_RXD[3:0], MII_RX_DV, MII_RX_ER, MII_RX_CLK)

The receiver functions correctly up to a MII_RX_CLK maximum frequency of 25 MHz + 1%. There is no minimum frequency requirement. In addition, the processor clock frequency must exceed the MII_RX_CLK frequency – 1%.

Table 29 provides information on the MII receive signal timing.

Table 29. MII Receive Signal Timing

Num	Characteristic	Min	Max	Unit
M1	MII_RXD[3:0], MII_RX_DV, MII_RX_ER to MII_RX_CLK setup	5	—	ns
M2	MII_RX_CLK to MII_RXD[3:0], MII_RX_DV, MII_RX_ER hold	5	—	ns
M3	MII_RX_CLK pulse width high	35%	65%	MII_RX_CLK period
M4	MII_RX_CLK pulse width low	35%	65%	MII_RX_CLK period

Figure 72 shows MII receive signal timing.

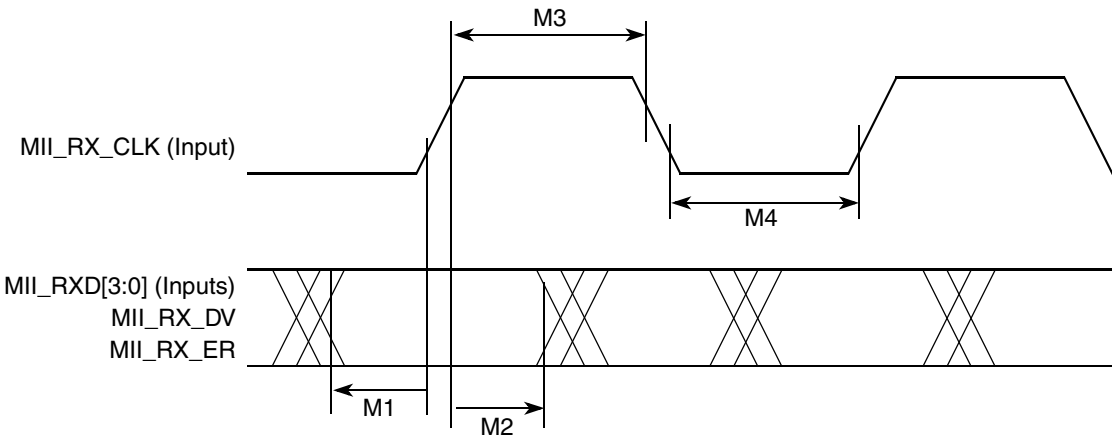


Figure 72. MII Receive Signal Timing Diagram